| Order Number |  | Package Number |
| :--- | :---: | :--- |
| 29F52SC | M24B | 24-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide |
| 29F52SPC | N24C | 24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide |
| 29F53SPC | N24C | 24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide |

Devices also available in Tape and Reel. Specify by appending the suffix letter " X " to the ordering code.
Logic Symbols


## Connection Diagrams

Pin Assignment for DIP and SOIC
29F52


Pin Assignment for DIP


Unit Loading/Fan Out

| Pin Names | Description | U.L. <br> HIGH/LOW | Input $\mathbf{I}_{\mathbf{I I}} / \mathbf{I}_{\mathbf{I L}}$ <br> Output $\mathbf{I}_{\mathbf{O H}} / \mathbf{I}_{\mathbf{O L}}$ |
| :--- | :--- | :---: | :---: |
|  | A-Register Inputs/ | $3.5 / 1.083$ | $70 \mu \mathrm{~A} / 0.65 \mathrm{~mA}$ |
| $\mathrm{~B}_{0}-\mathrm{B}_{7}$ | B-Register 3-STATE Outputs | $150 / 40(33.3)$ | $-3 \mathrm{~mA} / 24 \mathrm{~mA}(20 \mathrm{~mA})$ |
|  | B Register Inputs/ | $3.5 / 1.083$ | $70 \mu \mathrm{~A} / 0.65 \mathrm{~mA}$ |
| $\overline{\mathrm{OEA}}$ | A-Register 3-STATE Outputs | $600 / 106.6(80)$ | $-12 \mathrm{~mA} / 64 \mathrm{~mA}(48 \mathrm{~mA})$ |
| CPA | Output Enable A-Register | $1.0 / 1.0$ | $20 \mu \mathrm{~A} /-0.6 \mathrm{~mA}$ |
| $\overline{\text { CEA }}$ | A-Register Clock | $1.0 / 1.0$ | $20 \mu \mathrm{~A} /-0.6 \mathrm{~mA}$ |
| $\overline{\text { OEB }}$ | A-Register Clock Enable | $1.0 / 1.0$ | $20 \mu \mathrm{~A} /-0.6 \mathrm{~mA}$ |
| CPB | Output Enable B-Register | $1.0 / 1.0$ | $20 \mu \mathrm{~A} /-0.6 \mathrm{~mA}$ |
| $\overline{\mathrm{CEB}}$ | B-Register Clock | $1.0 / 1.0$ | $20 \mu \mathrm{~A} /-0.6 \mathrm{~mA}$ |
|  | B-Register Clock Enable | $1.0 / 1.0$ | $20 \mu \mathrm{~A} /-0.6 \mathrm{~mA}$ |

Output Control

| OE | Internal Q | Y-Output |  | Function |
| :---: | :---: | :---: | :---: | :---: |
|  |  | 29 F 52 | 29F53 |  |
| H | X | Z | Z | Disable Outputs |
| L | L | L | H | Enable Outputs |
| L | H | H | L | Enable Outputs |

L = LOW Voltage Level
$X=$ Immaterial
Z = HIGH Impedance
N = LOW-to-HIGH Transition
NC = No Change

Register Function Table (Applies to A or B Register)

| Inputs |  |  | Internal | Function |  |
| :---: | :---: | :---: | :---: | :--- | :---: |
| D | CP | CE | Q |  |  |
| X | X | H | NC | Hold Data |  |
| L | N | L | L | Load Data |  |
| H | N | L | H |  |  |




## Absolute Maximum Ratings（Note 1）

Storage Temperature
Ambient Temperature under Bias Junction Temperature under Bias $\mathrm{V}_{\mathrm{CC}}$ Pin Potential to Ground Pin Input Voltage（Note 2）
Input Current（Note 2）
Voltage Applied to Output

| in HIGH State（with $\mathrm{V}_{\mathrm{CC}}=0 \mathrm{~V}$ ） |  |
| :--- | ---: |
| Standard Output | -0.5 V to $\mathrm{V}_{\mathrm{CC}}$ |
| 3－STATE Output | -0.5 V to +5.5 V | 3－STATE Output

-0.5 V to +5.5 V
$-65^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$
$-55^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$
$-55^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$ -0.5 V to +7.0 V -0.5 V to +7.0 V -30 mA to +5.0 mA

## Recommended Operating

 Conditions| Free Air Ambient Temperature | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ |
| :--- | ---: |
| Supply Voltage | +4.5 V to +5.5 V |

Note 1：Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired．Functional operation under these conditions is not implied．
Note 2：Either voltage limit or current limit is sufficient to protect inputs．

Current Applied to Output

$$
\text { twice the rated } \mathrm{I}_{\mathrm{OL}}(\mathrm{~mA})
$$

## DC Electrical Characteristics

| Symbol | Parameter | Min | Typ | Max | Units | $\mathrm{V}_{\mathrm{cc}}$ | Conditions |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\mathrm{IH}}$ | Input HIGH Voltage | 2.0 |  |  | V |  | Recognized as a HIGH Signal |
| $\mathrm{V}_{\mathrm{IL}}$ | Input LOW Voltage |  |  | 0.8 | V |  | Recognized as a LOW Signal |
| $\mathrm{V}_{C D}$ | Input Clamp Diode Voltage |  |  | －1．2 | V | Min | $\mathrm{I}_{\mathrm{N}}=-18 \mathrm{~mA}$（Non I／O Pins） |
| $\mathrm{V}_{\mathrm{OH}}$ | Output HIGH $10 \% \mathrm{~V}_{\mathrm{CC}}$ <br> Voltage $10 \% \mathrm{~V}_{\mathrm{CC}}$ <br>  $10 \% \mathrm{~V}_{\mathrm{CC}}$ <br>  $5 \% \mathrm{~V}_{\mathrm{CC}}$ <br>  $5 \% \mathrm{~V}_{\mathrm{CC}}$ | $\begin{aligned} & 2.5 \\ & 2.4 \\ & 2.0 \\ & 2.7 \\ & 2.7 \end{aligned}$ |  |  | V | Min | $\begin{aligned} & \mathrm{l}_{\mathrm{OH}}=-1 \mathrm{~mA}\left(A_{n}\right) \\ & \mathrm{l}_{\mathrm{OH}}=-3 \mathrm{~mA}\left(\mathrm{~A}_{n}, B_{n}\right) \\ & \mathrm{l}_{\mathrm{OH}}=-15 \mathrm{~mA}\left(B_{n}\right) \\ & \mathrm{l}_{\mathrm{OH}}=-1 \mathrm{~mA}\left(A_{n}\right) \\ & \mathrm{I}_{\mathrm{OH}}=-3 \mathrm{~mA}\left(\mathrm{~A}_{n}, B_{n}\right) \end{aligned}$ |
| $\mathrm{V}_{\text {OL }}$ | Output LOW $10 \% \mathrm{~V}_{\mathrm{CC}}$ <br> Voltage $10 \% \mathrm{~V}_{\mathrm{CC}}$ |  |  | $\begin{gathered} \hline 0.5 \\ 0.55 \end{gathered}$ | V | Min | $\begin{aligned} & \text { loL }=24 \mathrm{~mA}\left(\mathrm{~A}_{\mathrm{n}}\right) \\ & \mathrm{lOL}=64 \mathrm{~mA}\left(\mathrm{~B}_{\mathrm{n}}\right) \end{aligned}$ |
| IH | Input HIGH Current |  |  | 20 | $\mu \mathrm{A}$ | Max | $\mathrm{V}_{\text {IN }}=2.7 \mathrm{~V}$（Non－I／O Pins） |
| $\mathrm{I}_{\text {BVI }}$ | Input HIGH Current <br> Breakdown Test |  |  | 100 | $\mu \mathrm{A}$ | Max | $\mathrm{V}_{\mathrm{IN}}=7.0 \mathrm{~V}$（Non－I／O Pins） |
| $\mathrm{I}_{\text {BVIT }}$ | Input HIGH Current Breakdown Test（I／O） |  |  | 1.0 | mA | Max | $\mathrm{V}_{\text {IN }}=5.5 \mathrm{~V}\left(\mathrm{~A}_{\mathrm{n}}, \mathrm{B}_{\mathrm{n}}\right)$ |
| IL | Input LOW Current |  |  | －0．6 | mA | Max | $\mathrm{V}_{\text {IN }}=0.5 \mathrm{~V}$（ （Non－I／O Pins） |
| $\mathrm{I}_{\mathrm{IH}}+\mathrm{l}_{\text {OZH }}$ | Output Leakage Current |  |  | 70 | $\mu \mathrm{A}$ | Max | $\mathrm{V}_{\text {OUT }}=2.7 \mathrm{~V}\left(\mathrm{~A}_{\mathrm{n}}, \mathrm{B}_{\mathrm{n}}\right)$ |
| $\mathrm{I}_{\text {IL }}+\mathrm{I}_{\text {OZL }}$ | Output Leakage Current |  |  | －650 | $\mu \mathrm{A}$ | Max | $\mathrm{V}_{\text {OUT }}=0.5 \mathrm{~V}\left(\mathrm{~A}_{\mathrm{n}}, \mathrm{B}_{\mathrm{n}}\right)$ |
| los | Output Short－Circuit Current | $\begin{gathered} \hline-60 \\ -100 \end{gathered}$ |  | $\begin{aligned} & \hline-150 \\ & -225 \end{aligned}$ | mA | Max | $\begin{aligned} & \mathrm{V}_{\text {OUT }}=0 \mathrm{~V}\left(\mathrm{~A}_{\mathrm{n}}\right) \\ & \mathrm{V}_{\text {OUT }}=0 \mathrm{~V}\left(\mathrm{~B}_{\mathrm{n}}\right) \end{aligned}$ |
| ${ }_{\text {cex }}$ | Output HIGH Leakage Current |  |  | 250 | $\mu \mathrm{A}$ | Max | $\mathrm{V}_{\text {OUT }}=\mathrm{V}_{\text {CC }}\left(\mathrm{A}_{\mathrm{n}}, \mathrm{B}_{\mathrm{n}}\right)$ |
| Izz | Bus Drainage Test |  |  | 500 | $\mu \mathrm{A}$ | 0．0V | $\mathrm{V}_{\text {OUT }}=5.25 \mathrm{~V}\left(\mathrm{~A}_{\mathrm{n}}, \mathrm{B}_{\mathrm{n}}\right)$ |
| $\mathrm{I}_{\mathrm{CCH}}$ | Power Supply Current |  | 130 | 190 | mA | Max | $\mathrm{V}_{\mathrm{O}}=$ HIGH |
| $\mathrm{I}_{\text {CCL }}$ | Power Supply Current |  |  | 190 | mA | Max | $\mathrm{V}_{\mathrm{O}}=$ LOW |
| $\mathrm{I}_{\text {ccz }}$ | Power Supply Current |  |  | 190 | mA | Max | $\mathrm{V}_{\mathrm{O}}=$ HIGH Z |



## AC Operating Requirements

| Symbol | Parameter | $\begin{gathered} \mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C} \\ \mathrm{~V}_{\mathrm{CC}}=+5.0 \mathrm{~V} \end{gathered}$ |  | $\begin{gathered} \mathrm{T}_{\mathrm{A}}=-55^{\circ} \mathrm{C} \text { to }+125^{\circ} \mathrm{C} \\ \mathrm{~V}_{\mathrm{CC}}=+5.0 \mathrm{~V} \end{gathered}$ |  | $\begin{gathered} \mathrm{T}_{\mathrm{A}}=0^{\circ} \mathrm{C} \text { to }+70^{\circ} \mathrm{C} \\ \mathrm{~V}_{\mathrm{CC}}=+5.0 \mathrm{~V} \end{gathered}$ |  | Units |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | Min | Max | Min | Max | Min | Max |  |
| $\begin{aligned} & \hline \mathrm{t}_{\mathrm{s}}(\mathrm{H}) \\ & \mathrm{t}_{\mathrm{S}}(\mathrm{~L}) \end{aligned}$ | Setup Time, HIGH or LOW $A_{n}$ or $B_{n}$ to CPA or CPB | $\begin{aligned} & 4.0 \\ & 4.0 \end{aligned}$ |  |  |  | $\begin{aligned} & 4.5 \\ & 4.5 \end{aligned}$ |  | ns |
| $\begin{aligned} & \hline \mathrm{t}_{\mathrm{H}}(\mathrm{H}) \\ & \mathrm{t}_{\mathrm{H}}(\mathrm{~L}) \end{aligned}$ | Hold Time, HIGH or LOW $A_{n}$ or $B_{n}$ to CPA or CPB | $\begin{aligned} & \hline 2.0 \\ & 2.0 \end{aligned}$ |  |  |  | $\begin{aligned} & 2.5 \\ & 2.5 \end{aligned}$ |  | ns |
| $\begin{aligned} & \hline \mathrm{t}_{\mathrm{S}}(\mathrm{H}) \\ & \mathrm{t}_{\mathrm{S}}(\mathrm{~L}) \end{aligned}$ | Setup Time, HIGH or LOW $\overline{\mathrm{CEA}}$ or $\overline{\mathrm{CEB}}$ to CPA or CPB | $\begin{aligned} & 1.0 \\ & 4.0 \end{aligned}$ |  |  |  | $\begin{aligned} & 1.5 \\ & 4.5 \end{aligned}$ |  | ns |
| $\begin{aligned} & \hline t_{\mathrm{H}}(\mathrm{H}) \\ & \mathrm{t}_{\mathrm{H}}(\mathrm{~L}) \end{aligned}$ | Hold Time, HIGH or LOW $\overline{\mathrm{CEA}}$ or $\overline{\mathrm{CEB}}$ to CPA or CPB | $\begin{aligned} & 2.0 \\ & 2.0 \end{aligned}$ |  |  |  | $\begin{aligned} & 2.5 \\ & 2.5 \end{aligned}$ |  | ns |
| $\begin{aligned} & \hline t_{w}(\mathrm{H}) \\ & t_{w}(\mathrm{~L}) \end{aligned}$ | $\begin{aligned} & \text { Pulse Width, HIGH or LOW } \\ & \text { CPA or CPB } \end{aligned}$ | $\begin{aligned} & \hline 3.0 \\ & 3.0 \end{aligned}$ |  |  |  | $\begin{aligned} & \hline 3.5 \\ & 3.5 \end{aligned}$ |  | ns |

Physical Dimensions inches（millimeters）unless otherwise noted



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